

**REMARKS**

At the outset, the Examiner is thanked for the thorough review and consideration of the pending application. The Office Action dated July 12, 2005 has been received and its contents carefully reviewed.

By this Amendment, Applicants have amended claims 1-3, 5, 8 and 11. Accordingly, claims 1-12 are currently pending in the present application. Reexamination and reconsideration of the pending claims is respectfully requested.

In the Office Action, the Examiner rejected claims 1-7 under 35 U.S.C. § 102(b) as being anticipated by Ono et al. (U.S. Patent No. 5,668,379); and rejected claims 8-12 under 35 U.S.C. § 103(a) as being unpatentable over Ono et al. Applicants respectfully traverse these rejections and reconsideration is requested.

Claim 1 is allowable over the cited references in that claim 1 recites a combination of elements including, for example, "...wherein a contact hole that electrically connects a drain electrode of the TFTs with a pixel electrode of the pixel region is formed over predetermined portions of the drain electrode and the pixel region to expose the insulating substrate through a gate insulating film and a passivation film..." None of the cited references including Ono et al., singly or in combination, teaches or suggests at least this feature of the claimed invention. Accordingly, Applicants respectfully submit that claim 1 is allowable over the cited references.

Claim 3 is allowable over the cited references in that claim 3 recites a combination of elements including, for example, "...a contact hole formed over the drain electrode and the pixel region to expose the substrate through a gate insulating film and a passivation film..." For similar reasons as discussed with respect to claim 1, none of the cited references including Ono et al., singly or in combination, teaches or suggests at least this feature of the claimed invention. Accordingly, Applicants respectfully submit that claim 3 and claims 6 and 7, which depend therefrom, are allowable over the cited references.

Claim 8 is allowable over the cited references in that claim 8 recites a combination of elements including, for example, "...forming a contact hole over a predetermined portion of the drain electrode and a pixel region adjacent to the drain electrode to expose the insulating substrate through the passivation film and a gate insulating film..." For similar reasons as


discussed with respect to claim 1, none of the cited references including Ono et al., singly or in combination, teaches or suggests at least this feature of the claimed invention. Accordingly, Applicants respectfully submit that claim 8 and claim 11, which depends therefrom, are allowable over the cited references.

Applicants believe the application is in condition for allowance and early, favorable action is respectfully solicited. If for any reason the Examiner finds the application other than in condition for allowance, the Examiner is requested to call the undersigned attorney at (202) 496-7500 to discuss the steps necessary for placing the application in condition for allowance. All correspondence should continue to be sent to the below-listed address.

If these papers are not considered timely filed by the Patent and Trademark Office, then a petition is hereby made under 37 C.F.R. §1.136, and any additional fees required under 37 C.F.R. §1.136 for any necessary extension of time, or any other fees required to complete the filing of this response, may be charged to Deposit Account No. 50-0911. Please credit any overpayment to deposit Account No. 50-0911. A duplicate copy of this sheet is enclosed.

Dated: November 10, 2005

Respectfully submitted,

By   
Eric Nuss  
Registration No.: 40,106  
McKENNA LONG & ALDRIDGE LLP  
1900 K Street, N.W.  
Washington, DC 20006  
(202) 496-7500  
Attorney for Applicant